Notice of References Cited

Application/Control No. 10/564,469	Reexamination	Applicant(s)/Patent Under Reexamination SHIBATA ET AL.	
Examiner	Art Unit		
Claire L. Rademaker	1795	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0134166 A1	07-2003	Skala et al.	429/17
*	В	US-2004/0009377 A1	01-2004	Iguchi, Masaru	429/13
*	С	US-2004/0038098 A1	02-2004	Imamura et al.	429/25
*	D	US-2005/0277010 A1	12-2005	Lamont et al.	429/034
*	E	US-2004/0137258 A1	07-2004	Meltser et al.	428/629
	F	US-			
	G	US-			
	Н	US-			
	l	US-			
	J	US-			
	К	US-			
	L	US-			- 11 /
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11354143 A	12-1999	Japan	SAITO, HAJIME	H01M 08/04
	0	JP 2002373682 A	12-2002	Japan	SUGAWARA et al.	H01M 08/04
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	IPDL Machine Translation and Abstract in English of JP 2002-373682.
(F 1)	٧	IPDL Machine Translation and Abstract in English of JP 11-354143.
	w	
	×	

*A copy of this reference is not being furnished with this Office acti on. (See MPEP § 707.05(a).)

Dates in MM-YYYYY format are publication dates. Classifications may be US or foreign.